

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/080,562	KAMO ET AL.
	Examiner Dah-Wei D. Yuan	Art Unit 1745

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
429	12	4/27/2006	DWY
429	30	4/27/2006	DWY
429	32	4/27/2006	DWY